

ABSTRACT OF THE DISCLOSURE

A test system includes a test data generator to provide test data (e.g., a test pattern) to a subject circuit (e.g., a digital television video circuit). The test data is functionally to verify the subject circuit. The functional verification of the subject circuit is performed utilizing an output of the subject circuit generated responsive to the test data in accordance with an operational functionality of the subject circuit. The test data generator is also coupled to provide the test data to a built-in self-test (BIST) circuit so as to enable the built-in self-test circuit to receive the test data